

Configuration memory - FL MEM PLUG - 2891259

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Exchangeable configuration memory of the device settings for simple device exchange and set-up

Product Description

Memory plug, configuration memory, replaceable

Key Commercial Data

Packing unit	1 pc
Weight per Piece (excluding packing)	17.4 g
Custom tariff number	84717098
Country of origin	Germany

Technical data

Note

Utilization restriction	EMC: class A product, see manufacturer's declaration in the download area
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Dimensions

Width	16 mm
Height	49 mm

Ambient conditions

Degree of protection	IP20
Ambient temperature (operation)	0 °C ... 55 °C (non-condensing)
Ambient temperature (storage/transport)	-20 °C ... 70 °C
Permissible humidity (operation)	10 % ... 95 % (non-condensing)
Permissible humidity (storage/transport)	10 % ... 95 % (non-condensing)

Function

Basic functions	Configuration memory (plug-in)
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General

Mounting type	In the host system
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General

Type AX	Fine granularity
Net weight	18.9 g

Conformity with EMC directives

Developed in acc. with standard	IEC 61000-6.2
Test standard	IEC 61000-4-2 (ESD)
Test result	Criterion B
Test standard	IEC 61000-4-3 (immunity to radiated interference)
Test result	Criterion A
Test standard	IEC 61000-4-4 (burst)
Test result	Criterion A
Test standard	IEC 61000-4-5 (surge)
Test result	Criterion A
Test standard	IEC 61000-4-6 (immunity to conducted interference)
Test result	Criterion A
Test standard	IEC 61000-4-8 (immunity to magnetic fields)
Test result	Criterion A
Test standard	EN 55022 (emitted interference)
Test result	Criterion A

Standards and Regulations

Electromagnetic compatibility	Conformance with EMC Directive 2004/108/EC
Developed in acc. with standard	IEC 61000-6.2
Test standard	IEC 61000-4-2 (ESD)
Test result	Criterion B
Test standard	IEC 61000-4-3 (immunity to radiated interference)
Test result	Criterion A
Test standard	IEC 61000-4-4 (burst)
Test result	Criterion A
Test standard	IEC 61000-4-5 (surge)
Test result	Criterion A
Test standard	IEC 61000-4-6 (immunity to conducted interference)
Test result	Criterion A
Test standard	IEC 61000-4-8 (immunity to magnetic fields)
Test result	Criterion A
Test standard	EN 55022 (emitted interference)
Test result	Criterion A
Noise emission	EN 61000-6-3/-4

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Standards and Regulations

Noise immunity	EN 61000-6-2:2005
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Classifications

eCl@ss

eCl@ss 4.0	27250501
eCl@ss 4.1	27250501
eCl@ss 5.0	27250501
eCl@ss 5.1	27250501
eCl@ss 6.0	27250501
eCl@ss 7.0	27250501
eCl@ss 8.0	27242212

ETIM

ETIM 2.0	EC000734
ETIM 3.0	EC000734
ETIM 4.0	EC000734
ETIM 5.0	EC000192

UNSPSC

UNSPSC 6.01	43172015
UNSPSC 7.0901	43201404
UNSPSC 11	43172015
UNSPSC 12.01	43201410
UNSPSC 13.2	43201410